

# SYMPOSIUM ON CHEMICAL ANALYSIS OF INORGANIC SOLIDS BY MEANS OF THE MASS SPECTROMETER

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PRESENTED AT  
MEETING OF COMMITTEE E-2 ON  
EMISSION SPECTROSCOPY  
Atlantic City, N. J., June 20, 1951



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*Special Technical Publication No. 149*

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Published by the  
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NOTE.—The Society is not responsible, as a body, for the statements  
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## FOREWORD

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It has been the practice of Committee E-2 on Emission Spectroscopy to sponsor symposia at intervals of a few years on subjects of interest to the committee, particularly with respect to instrumental analysis.

This Symposium on Chemical Analysis of Inorganic Solids by Means of the Mass Spectrometer was held at a meeting of Committee E-2 during the Fifty-fourth Annual Meeting of the Society, Atlantic City, N. J., June 20, 1951. The Symposium departs somewhat from past practice in that it involves a different field of spectroscopy, but one that offers promise as a means of parallel analysis of the materials now being analyzed by optical spectroscopy. This new application of mass spectrometry may employ some of the techniques of optical spectroscopy, including the use of the spark to volatilize substances, and it undoubtedly is faced with some of the ever-present problems, including sampling.

The growing interest in analytical applications of mass spectrometry in general was shown recently by the organization of ASTM Committee E-14 on Mass Spectrometry, which will carry out future ASTM activities in this field.

Committee E-2 is indebted to the speakers for their generous participation in the Symposium. The program was arranged by E. B. Ashcraft, Westinghouse Electric Corp., who also served as chairman of the session.

B. F. SCRIBNER, *Chairman*  
Committee E-2 on  
Emission Spectroscopy

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